

## 18A, 200V N-CHANNEL MOSFET

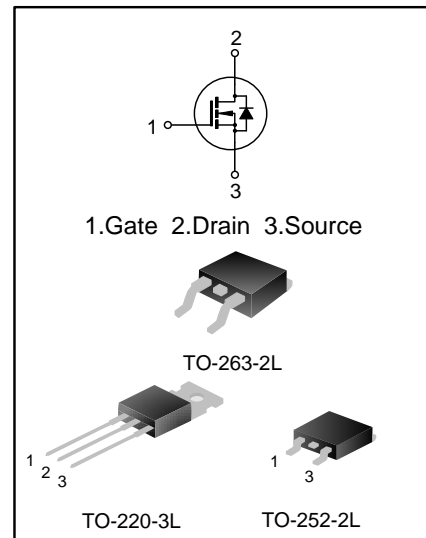
### GENERAL DESCRIPTION

SVD640T/D/S is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan proprietary S-Rin™ structure VDMOS technology. The improved process and cell structure have been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are widely used in AC-DC power supplies, DC-DC converters and H-bridge PWM motor drivers.

### FEATURES

- ◆ 18A,200V, $R_{DS(on)(typ.)}=0.12\Omega@V_{GS}=10V$
- ◆ Low gate charge
- ◆ Low Crss
- ◆ Fast switching
- ◆ Improved dv/dt capability



### ORDERING INFORMATION

Part No.	Package	Marking	Hazardous Substance Control	Packing Type
SVD640T	TO-220-3L	SVD640T	Pb free	Tube
SVD640D	TO-252-2L	SVD640D	Halogen free	Tube
SVD640DTR	TO-252-2L	SVD640D	Halogen free	Tape&Reel
SVD640S	TO-263-2L	SVD640S	Halogen free	Tube
SVD640STR	TO-263-2L	SVD640S	Halogen free	Tape&Reel

**ABSOLUTE MAXIMUM RATINGS (T<sub>c</sub>=25°C unless otherwise noted)**

Characteristics	Symbol	Ratings		Unit
		SVD640T/S	SVD640D	
Drain-Source Voltage	V <sub>DS</sub>	200		V
Gate-Source Voltage	V <sub>GS</sub>	±20		V
Drain Current	I <sub>D</sub>	T <sub>C</sub> =25°C		A
		T <sub>C</sub> =100°C		
Drain Pulsed Current	I <sub>DM</sub>	72		A
Power Dissipation(T <sub>C</sub> =25°C) -Derate above 25°C	P <sub>D</sub>	150	110	W
		1.2	0.88	W/°C
Single Pulsed Avalanche Energy (Note 1)	E <sub>AS</sub>	L=30mH		mJ
		L=10mH		mJ
Operation Junction Temperature Range	T <sub>J</sub>	150		°C
Storage Temperature Range	T <sub>stg</sub>	-65~+150		°C

**THERMAL CHARACTERISTICS**

Characteristics	Symbol	Typ.		Unit.
		SVD640T/S	SVD640D	
Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	0.83	1.14	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	62.5	62.0	°C/W

**ELECTRICAL CHARACTERISTICS (T<sub>c</sub>=25°C unless otherwise noted)**

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit.
Drain -Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	200	--	--	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =200V, V <sub>GS</sub> =0V	--	--	1	μA
		V <sub>DS</sub> =200V, V <sub>GS</sub> =0V, T <sub>C</sub> =125°C	--	--	1.0	
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	--	--	±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> =250μA	2.0	3.0	4.0	V
Static Drain- Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =9A	--	0.12	0.15	Ω
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1.0MHz	--	1108	--	pF
Output Capacitance	C <sub>oss</sub>		--	160	--	
Reverse Transfer Capacitance	C <sub>rss</sub>		--	34	--	
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =100V, V <sub>GS</sub> =10V, R <sub>G</sub> =2.5Ω, I <sub>D</sub> =11A (Notes2, 3)	--	15	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	47	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	110	--	
Turn-off Fall Time	t <sub>f</sub>		--	36	--	
Total Gate Charge	Q <sub>g</sub>	V <sub>DD</sub> =160V, V <sub>GS</sub> =10V, I <sub>D</sub> =11A (Notes2, 3)	--	41	--	nC
Gate-Source Charge	Q <sub>gs</sub>		--	6.0	--	
Gate-Drain Charge	Q <sub>gd</sub>		--	20	--	

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS**

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I <sub>S</sub>	Integral Reverse p-n Junction	--	--	18	A
Pulsed Source Current	I <sub>SM</sub>	Diode in the MOSFET	--	--	72	
Diode Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> =11A, V <sub>GS</sub> =0V	--	--	1.5	V
Reverse Recovery Time	T <sub>rr</sub>	V <sub>DD</sub> =50V, di/dt=100A/μS,	--	160	--	ns
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> =11A (Note 2)	--	0.98	--	μC

**Notes:**

- V<sub>DD</sub>=100V, R<sub>G</sub>=25Ω, starting T<sub>J</sub>=25°C;
- Pulse Test: Pulse width ≤300μs, Duty cycle≤2%;
- Essentially independent of operating temperature.

**TYPICAL CHARACTERISTICS**

Figure 1. On-Region Characteristics

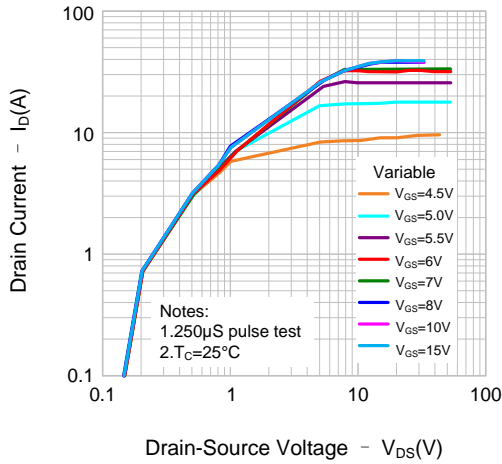


Figure 2. Transfer Characteristics

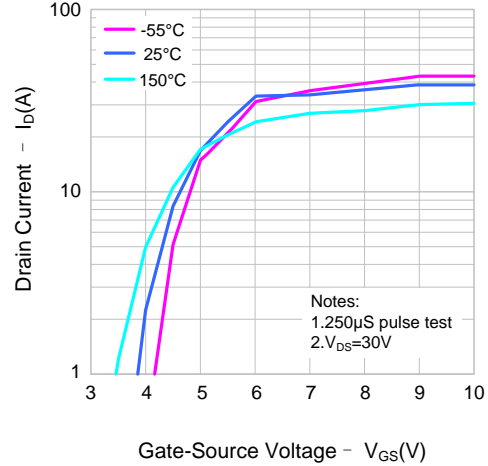


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

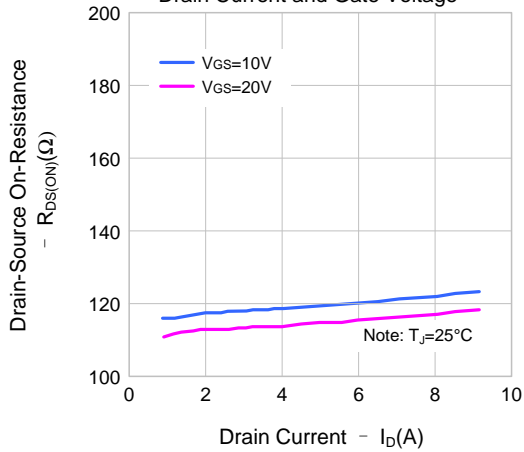


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

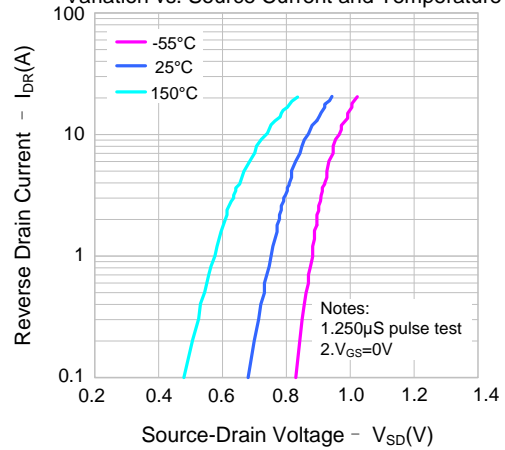


Figure 5. Capacitance Characteristics

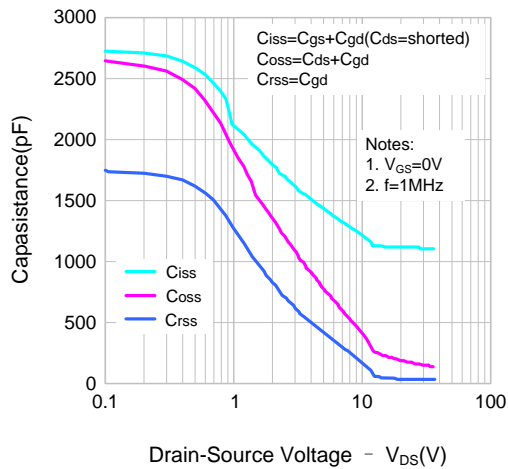
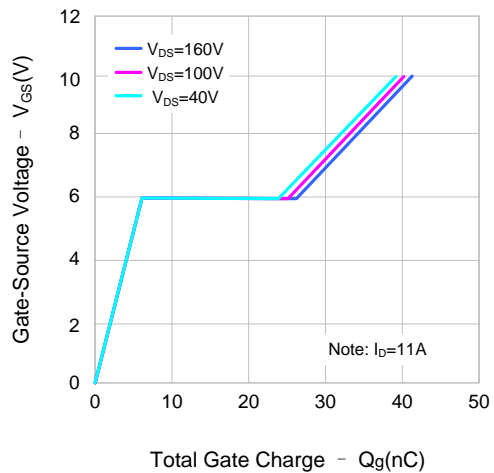
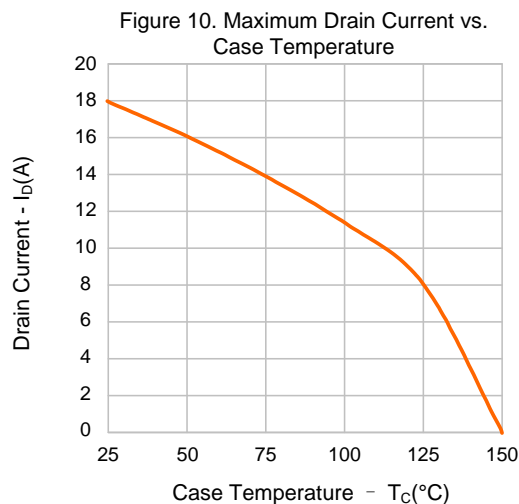
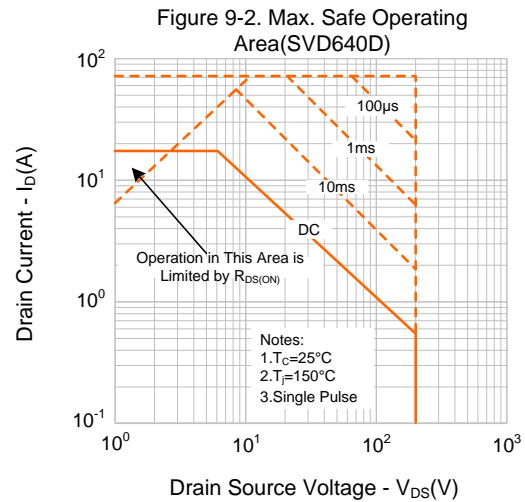
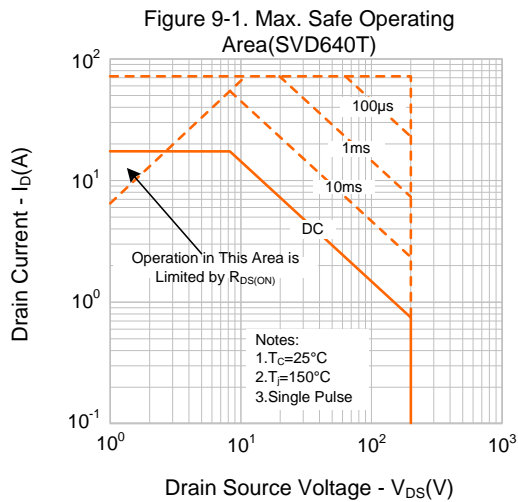
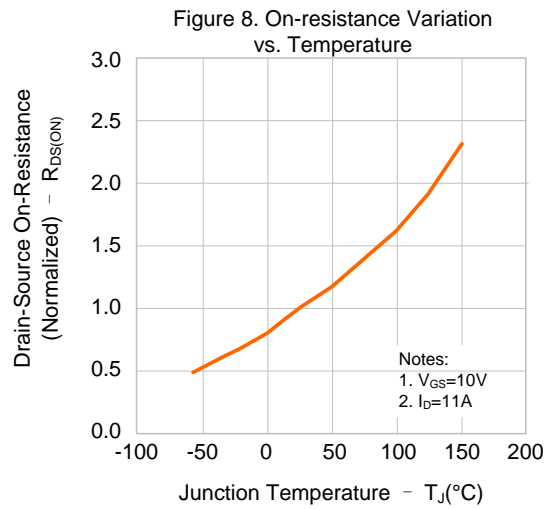
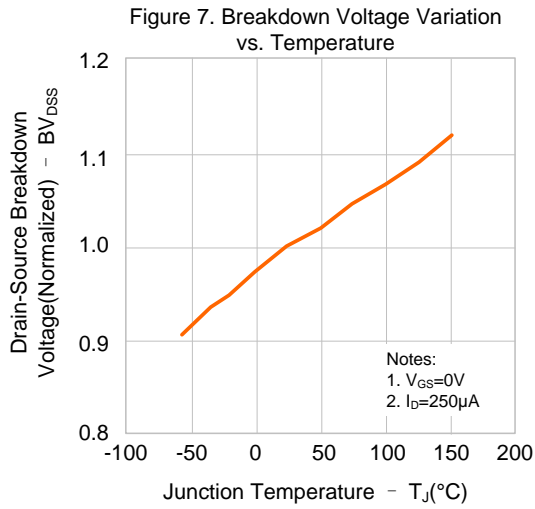


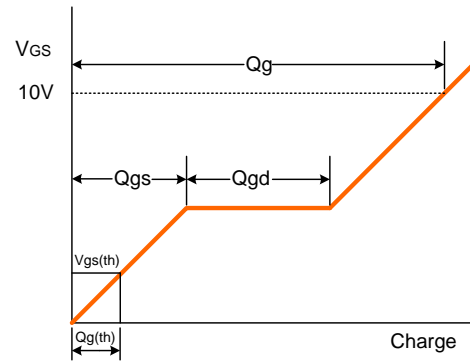
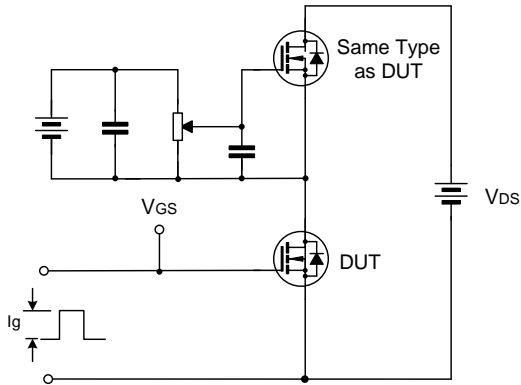
Figure 6. Gate Charge Characteristics



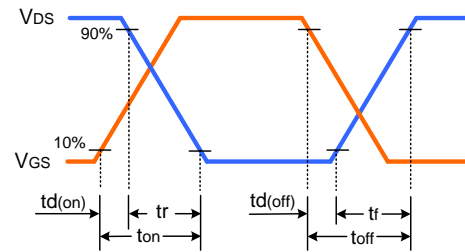
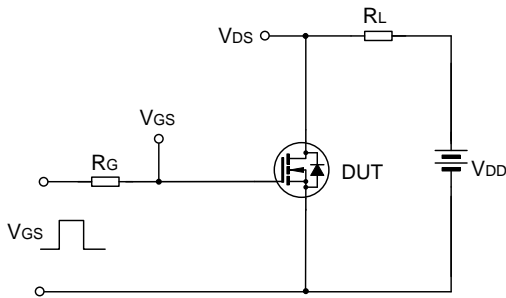
**TYPICAL CHARACTERISTICS(continued)**



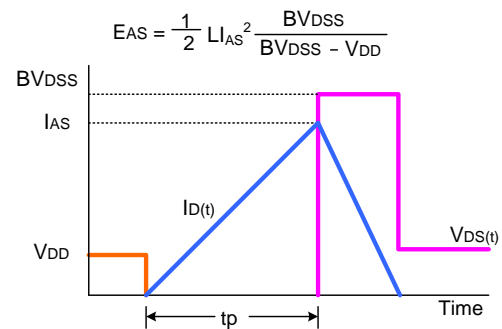
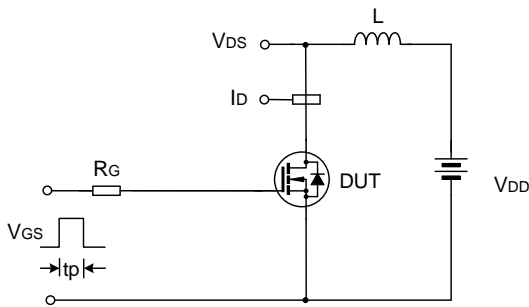
**TYPICAL TEST CIRCUIT**



Gate Charge Test Circuit & Waveform



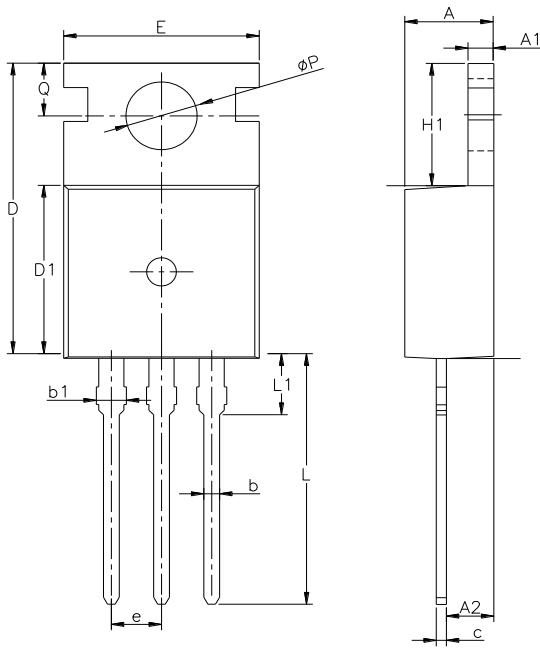
Resistive Switching Test Circuit & Waveform



Unclamped Inductive Switching Test Circuit & Waveform

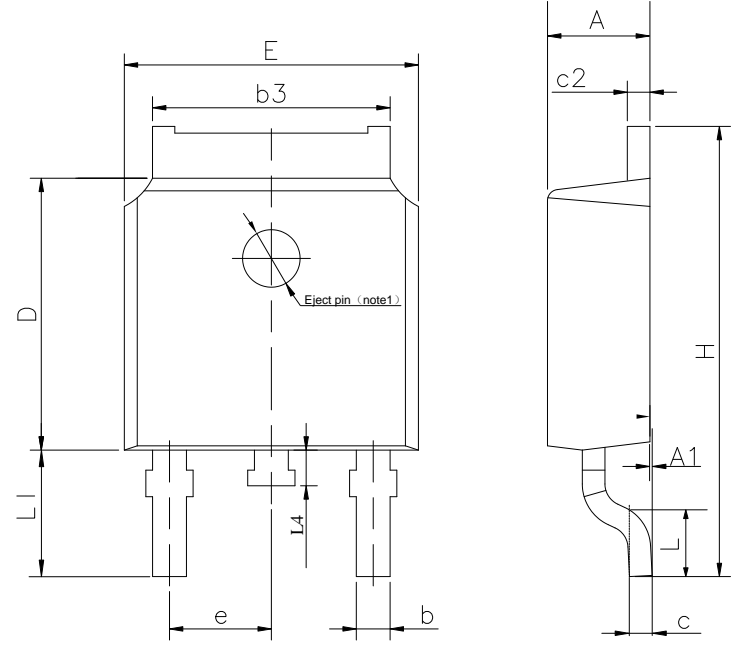
**PACKAGE OUTLINE**

**TO-220-3L** **UNIT: mm**



SYMBOL	MIN	NOM	MAX
A	4.30	4.50	4.70
A1	1.00	1.30	1.50
A2	1.80	2.40	2.80
b	0.60	0.80	1.00
b1	1.00	—	1.60
c	0.30	—	0.70
D	15.10	15.70	16.10
D1	8.10	9.20	10.00
E	9.60	9.90	10.40
e	2.54BSC		
H1	6.10	6.50	7.00
L	12.60	13.08	13.60
L1	—	—	3.95
φP	3.40	3.70	3.90
Q	2.60	—	3.20

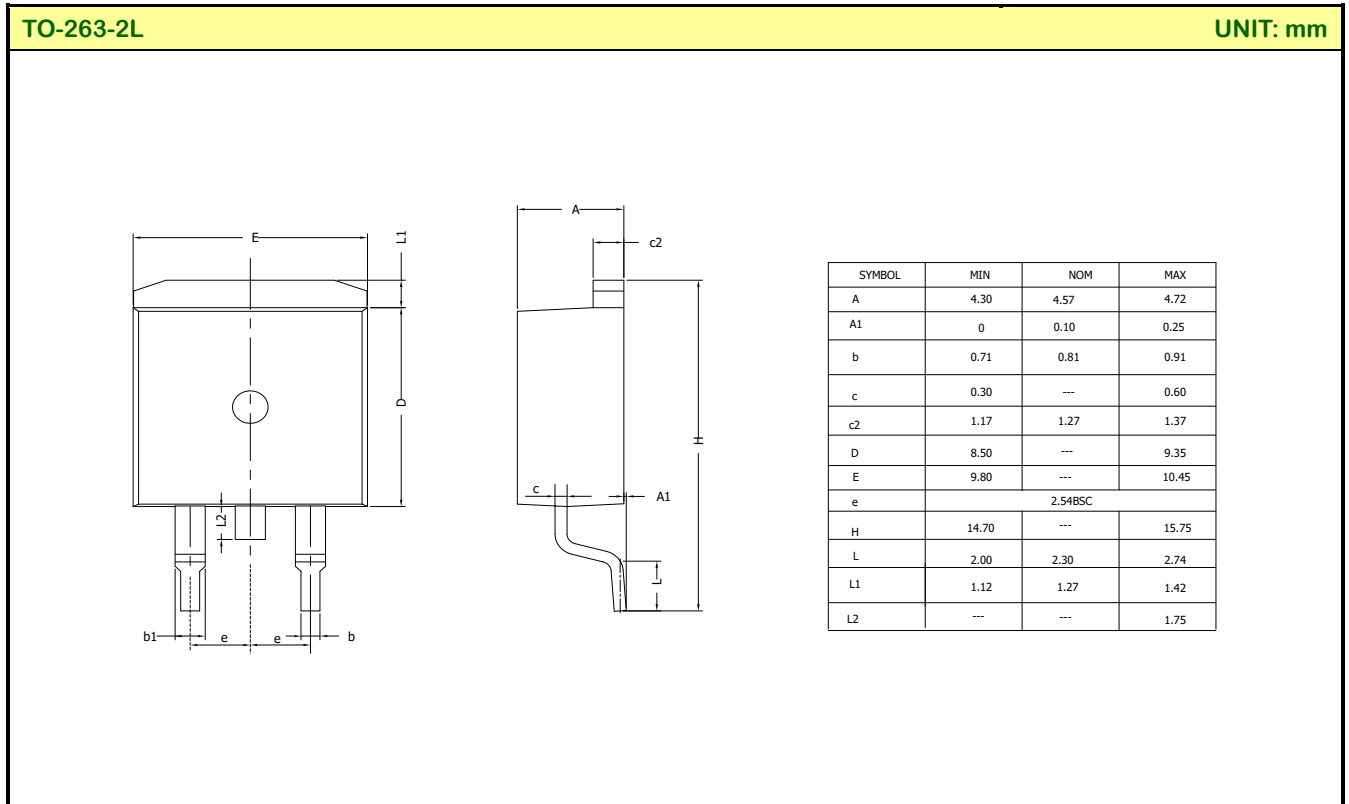
**TO-252-2L** **UNIT: mm**



SYMBOL	MIN	NOM	MAX
A	2.10	2.30	2.50
A1	0	---	0.127
b	0.66	0.76	0.89
b3	5.10	5.33	5.46
c	0.45	---	0.65
c2	0.45	---	0.65
D	5.80	6.10	6.40
E	6.30	6.60	6.90
e	2.30TYP		
H	9.60	10.10	10.60
L	1.40	1.50	1.70
L1	2.90REF		
L4	0.60	0.80	1.00

**NOTE1** : There are two conditions for this position:has an eject pin or has no eject pin.

**PACKAGE OUTLINE (continued)**



**Important notice :**

- The instructions are subject to change without notice! Customers should obtain the latest relevant information before placing orders and should verify that such information is complete and current.
- Our products are consumer electronic products, and / or civil electronic products.
- When using our products, please do not exceed the maximum rating of the products, otherwise the reliability of the whole machine will be affected. There is a certain possibility of failure or malfunction of any semiconductor product under specific conditions. The buyer is responsible for complying with safety standards and taking safety measures when using our products for system design, sample and whole machine manufacturing, so as to avoid potential failure risk that may cause personal injury or property loss.
- It is strongly recommended to identify the trademark when buying our products. Please contact us if there is any question.
- When exporting, using and reselling our products, buyer must comply with the international export control laws and regulations of China, the United States, the United Kingdom, the European Union and other countries & regions.
- Product promotion is endless, our company will wholeheartedly provide customers with better products!
- Website: <http://www.silan.com.cn>



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Part No.: SVD640T/D/S Document Type: Datasheet  
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Rev.: 1.4

Revision History:

1. Add SVD640S(To-263-2L) encapsulation
  2. Add parameters and curves with SVD640T
  3. Modify ORDERING INFORMATION
  4. Modify TYPICAL TEST CIRCUIT
  5. Modify Important notice
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Rev.: 1.3

Revision History:

1. Add the EAS value under L=10mH
  2. Update the package outline of TO-220-3L
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Rev.: 1.2

Revision History:

1. Delete the package information of TO-220F-3L
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Rev.: 1.1

Revision History:

1. Modify the package information of TO-220F-3L
  2. Modify the package information of TO-252-2L
  3. Modify the package information of TO-220-3L
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Rev.: 1.0

Revision History:

1. First release
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